

DEVICE FOR DETERMINING THE PARAMETERS OF DEVELOPING SURFACE CRACKS

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US3786679

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US4331035

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A device for measuring the parameters of developing surface cracks comprises a sensitive element (1) applied to a dielectric sublayer (2) at the point of expected development of a surface crack (11) and comprised of a number of conductors (4', 4'', ... 4<n>), and further comprises a measuring circuit (3) electrically connected to the sensitive element (1) in which the ends of the conductors (4', 4'', ... 4<n>) are electrically interconnected in series by their main bridges (5', 5'', ... 5<n-1>), the sensitive element being also provided with additional bridges (6', 6'', ... 6<n-1>) each of which is located opposite a main bridge (5', 5'', ... 5<n-1>).

